



Sheet 1 of 4

PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 219.005-C1-US	SERIAL NUMBER 10/790,276
	APPLICANT(S) Yamada et al.	
	FILING DATE March 1, 2004	GROUP ART UNIT 2825-2125

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
Qh n	4,571,685	2/1986	Kamoshida	—	—	
Q. P	6,055,463	4/2000	Cheong et al.	—	—	
Q. P	6,314,379	11/2001	Hu et al.	—	—	
Q. P	6,338,001	1/2002	Steffan et al.	—	—	
Qh r	6,542,830	4/2003	Mizuno et al.	—	—	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER <i>Albert W. Palmer</i>	ALBERT W. PALMER PATENT EXAMINER	DATE CONSIDERED 9-14-04
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.		



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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
Arr	3,614,608	10/1971	Giedd	—	—	
Arr	4,949,162	8/1990	Tamaki et al.	—	—	
Arr	4,988,877	1/1991	Stokowski et al.	—	—	
Arr	5,001,536	3/1991	Fukuzawa et al.	—	—	
Arr	5,089,774	2/1992	Nakano	—	—	
Arr	5,132,507	7/1992	Nakano	—	—	
Arr	5,280,176	1/1994	Jach et al.	—	—	
Arr	5,327,012	7/1994	Yano et al.	—	—	
Arr	5,365,034	11/1994	Kawamura et al.	—	—	
Arr	5,412,210	5/1995	Todokoro et al.	—	—	
Arr	5,453,994	9/1995	Kawamoto et al.	—	—	
Arr	5,493,236	2/1996	Ishii et al.	—	—	
Arr	5,637,186	6/1997	Liu et al.	—	—	
Arr	5,757,198	5/1998	Shida et al.	—	—	

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EXAMINER Albert W. Paladini	ALBERT W. PALADINI PATENT EXAMINER	DATE CONSIDERED 9-14-04
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PTO (Patent Office) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 219.005-C1-US	SERIAL NUMBER 10/790,276
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FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
AWP	03-205573	9/1991	Japan	—	—	
AWP	04-062857	2/1992	Japan	—	—	
AWP	06-273297	9/1994	Japan	—	—	
AWP	07-066172	3/1995	Japan	—	—	
AWP	08-005528	1/1996	Japan	—	—	Y
AWP	08-313244	11/1996	Japan	—	—	
AWP	09-061142	3/1997	Japan	—	—	Y
AWP	10-281746	10/1998	Japan	—	—	
AWP	10-300450	11/1998	Japan	—	—	
AWP	11-026343	1/1999	Japan	—	—	
AWP	2000-164715	6/2000	Japan	—	—	
AWP	2000-180143	6/2000	Japan	—	—	
AWP	2000-124276	4/2000	Japan	—	—	
AWP	2000-174077	6/2000	Japan	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

AWP

ALBERT W. PALADIN
PATENT EXAMINER

DATE CONSIDERED

9-14-04

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BWP	50-63990	5/1975	Japan	—	—	Y
AWP	57-6310	1/1982	Japan	—	—	Y
AWP	62-19707	1/1987	Japan	—	—	Y
AWP	63-9807	1/1988	Japan	—	—	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	"An In-Line Contact and Via Hole Inspection Method Using Electron Beam Compensation Current", Yamada et al., IEEE 1999, Doc. No. 0-7803-5413-3/99, available from http://www.fabsol.com/us/images/library/21.pdf

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